

Abstract

The present invention relates to a device and a method for characterizing spheroids.

The to-be-characterized spheroid (6) is introduced into a tube (1, 2) of an electrically insulating material and with an inner diameter which is smaller than the diameter of the to-be-characterized spheroid (6) in such a manner that the latter is in mechanical contact over the entire circumference with the inner wall of the electrically insulated tube (1,2). Electrodes (3, 4) are disposed on both sides of the spheroid (6) in the tube. By means of these electrodes, a current flow can be generated through the spheroid (6) and the resulting drop in voltage at the spheroid can be measured. The invented arrangement and the corresponding method permits producing an impedance spectrum of spheroids with high sensitivity, thereby realizing rapid and nondestructive characterization of spheroids. (figure 2).